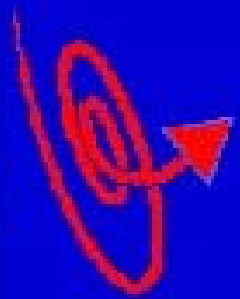


How IBIS Models Relate to SI, PI, and EMI-EMC

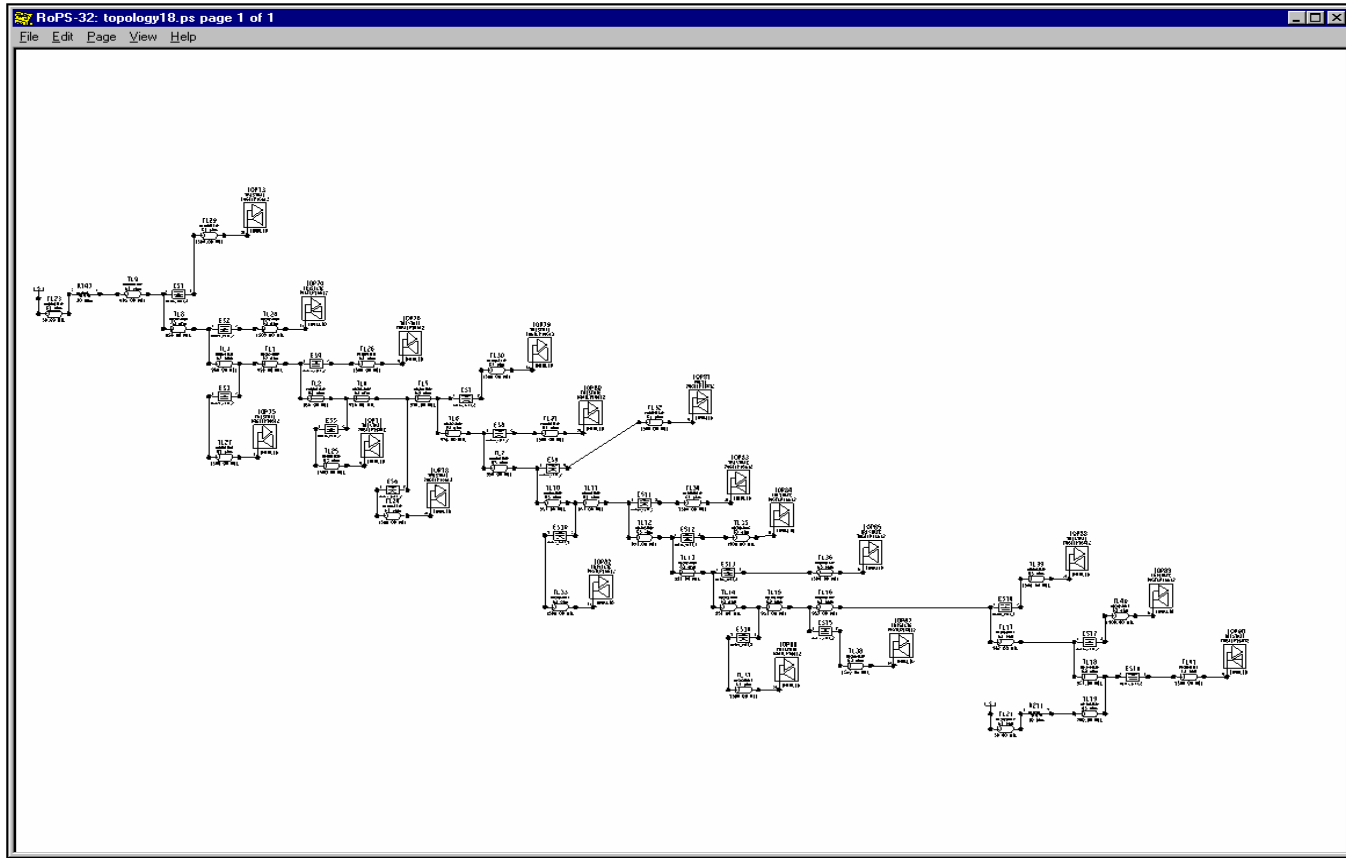
Roy Leventhal
DesignCon 2009
IBIS Summit Meeting
Santa Clara, CA
February 5, 2009



LEVENTHAL DESIGN & COMMUNICATIONS

Specializing in Modeling and Simulation Services

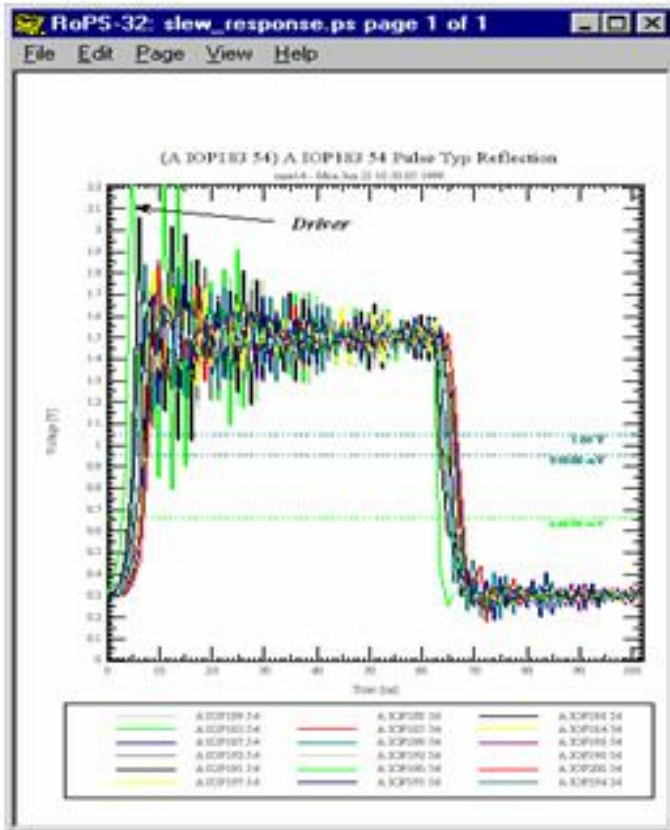
An Example of a Complex Network



An 18-Slot Bi-Directional Backplane Bus



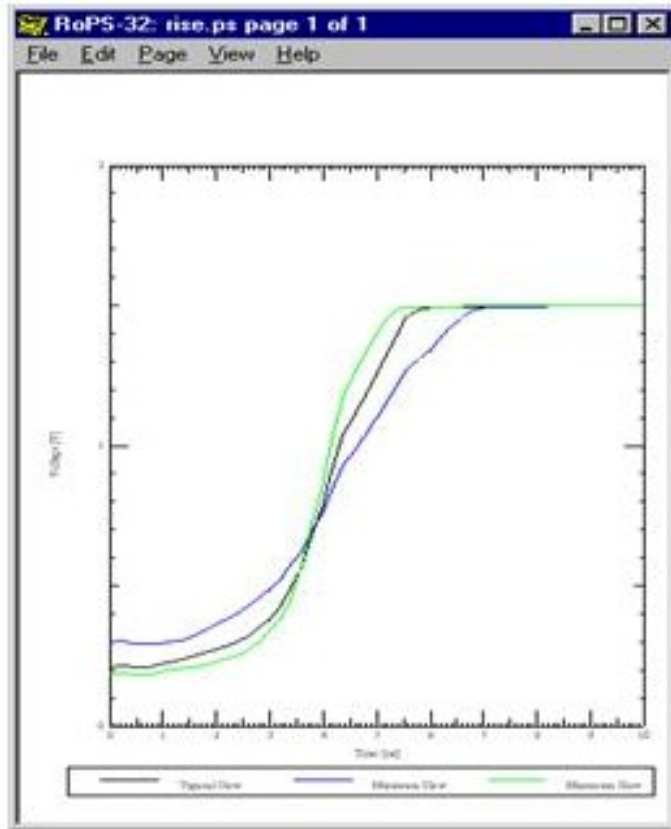
Simulation Results from too Simple a Model



- **Complex nets are hard to terminate and have many reflections**
- **Simple dV/dt modeling and device behavior is inadequate**
- **V-T curves need to be modeled for correct results in GTL/GTLP busses**

IBIS Modeling of V-T Curves

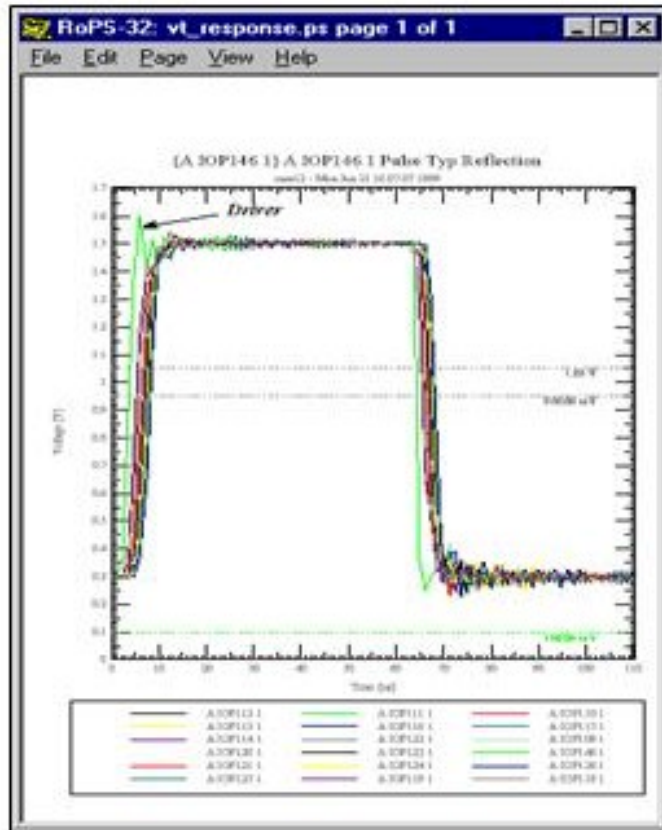
How GTLP Really Behaves



- This slide shows how to correctly model GTL/GTLP
- Soft turn-on/turn-off removes many high-frequency components (think about Fourier transformation) from driving the line
- The results of the change in modeling detail are shown next:



Better Models Give Better Results



“Everything should be as simple as possible *and no simpler.*”

-----Albert Einstein

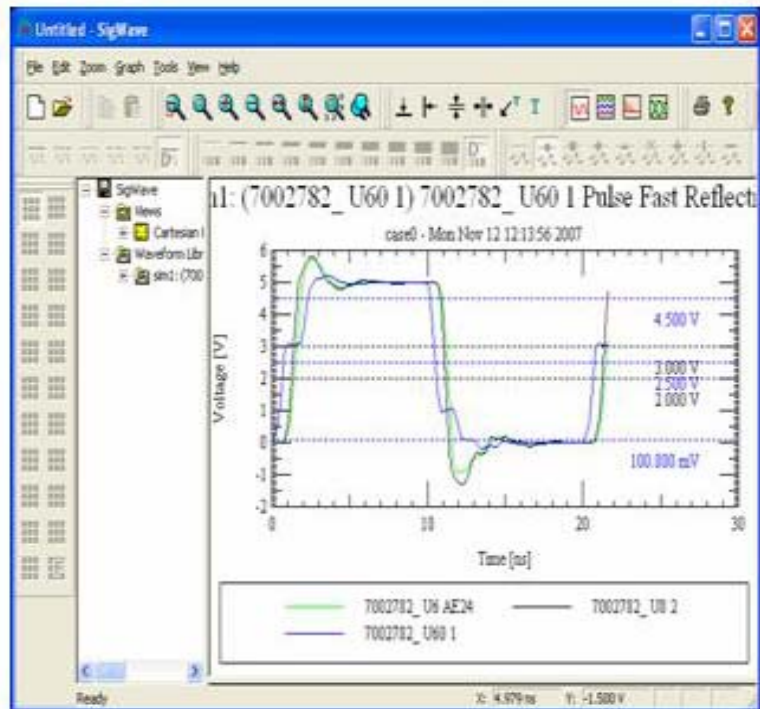


66MHz Clock Topology as Modified

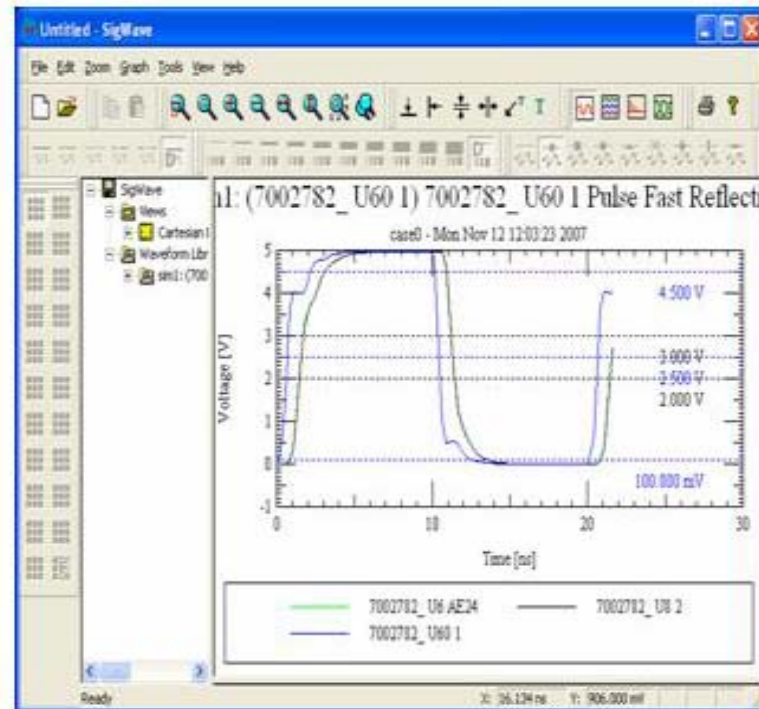
Courtesy of Hamilton-Sundstrand



How SI is Affected by Overshoot



Before Termination

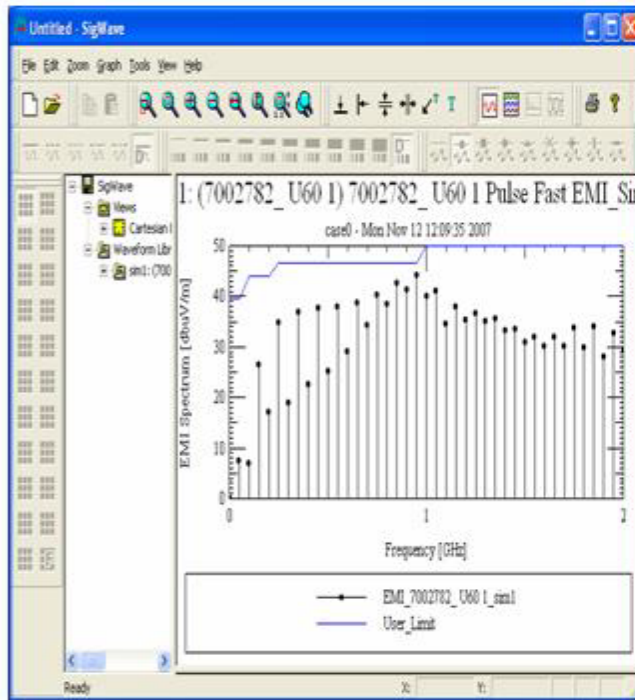


After Termination

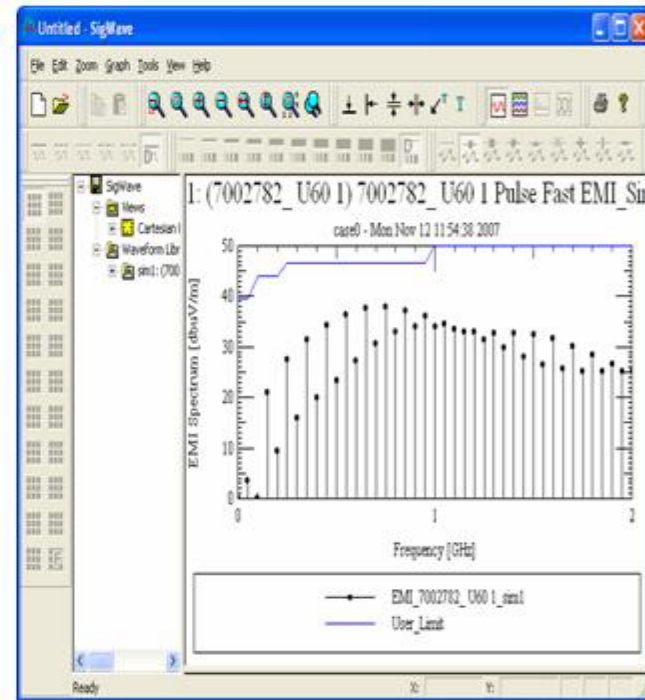
Before termination, SI and stress on the receiver is not a high concern – the real payoff will be in EMI control as shown in the next slide.



How EMI is Affected by Overshoot



Before Termination

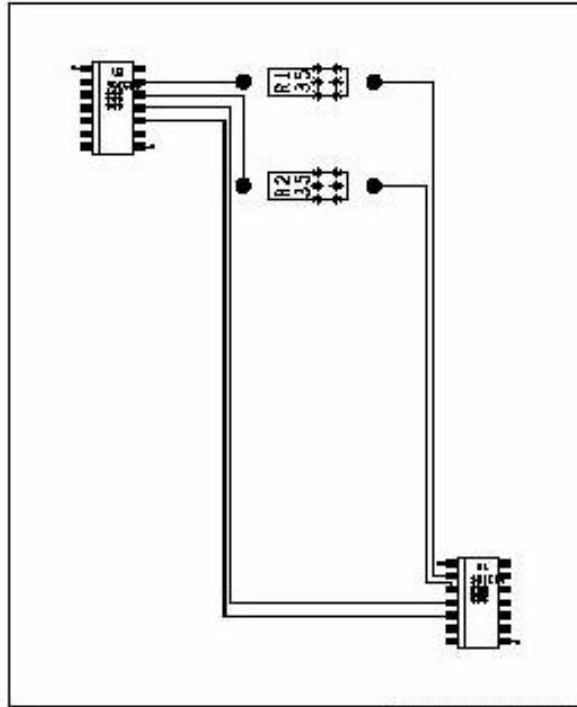


After Termination

The SI Engineer has to manage harmonics out to about the 5th .
The EMI engineer has to manage harmonics out to, perhaps, the 100th.



Example of Virtual Test Board



Layout of the Test Board

The board on the left has the following stackup:

top: 1.2 mil Cu signal $Z_0 = 89\Omega$

next: 12 mil FR4 ($\epsilon_r = 4.5$)

next: 1.2 mil Cu shield Vcc

next: 12 mil FR4

next: 1.2 mil Cu shield GND

next: 12 mil FR4

bottom: 1.2 mil Cu signal $Z_0 = 89\Omega$

Etch width is nominally 6 mils

For the shielded version outer shield layers of 1.2 mil Cu spaced by 12 mils of FR4 were added

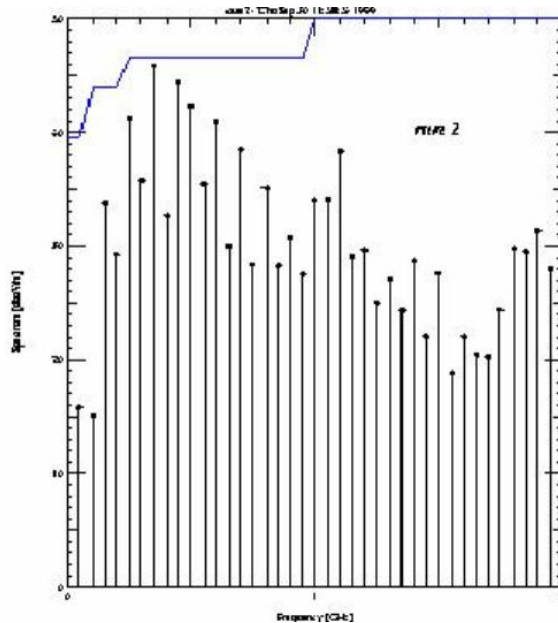
The nominal 6 mil etch on such an inner layer results in $Z_0 = 59.6\Omega$

The board is about 3 inches long.

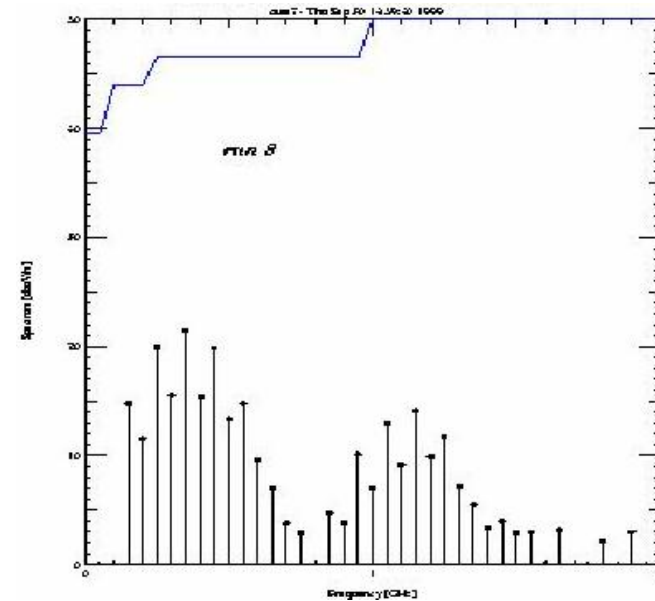
Stackup of the Test Board

Virtual Test Board

Before and After EMI Treatment



**Unshielded, Unterminated,
Non-Constant Impedance Net**



**Shielded, Terminated,
Constant Impedance Net**



Near Field EMI Simulators

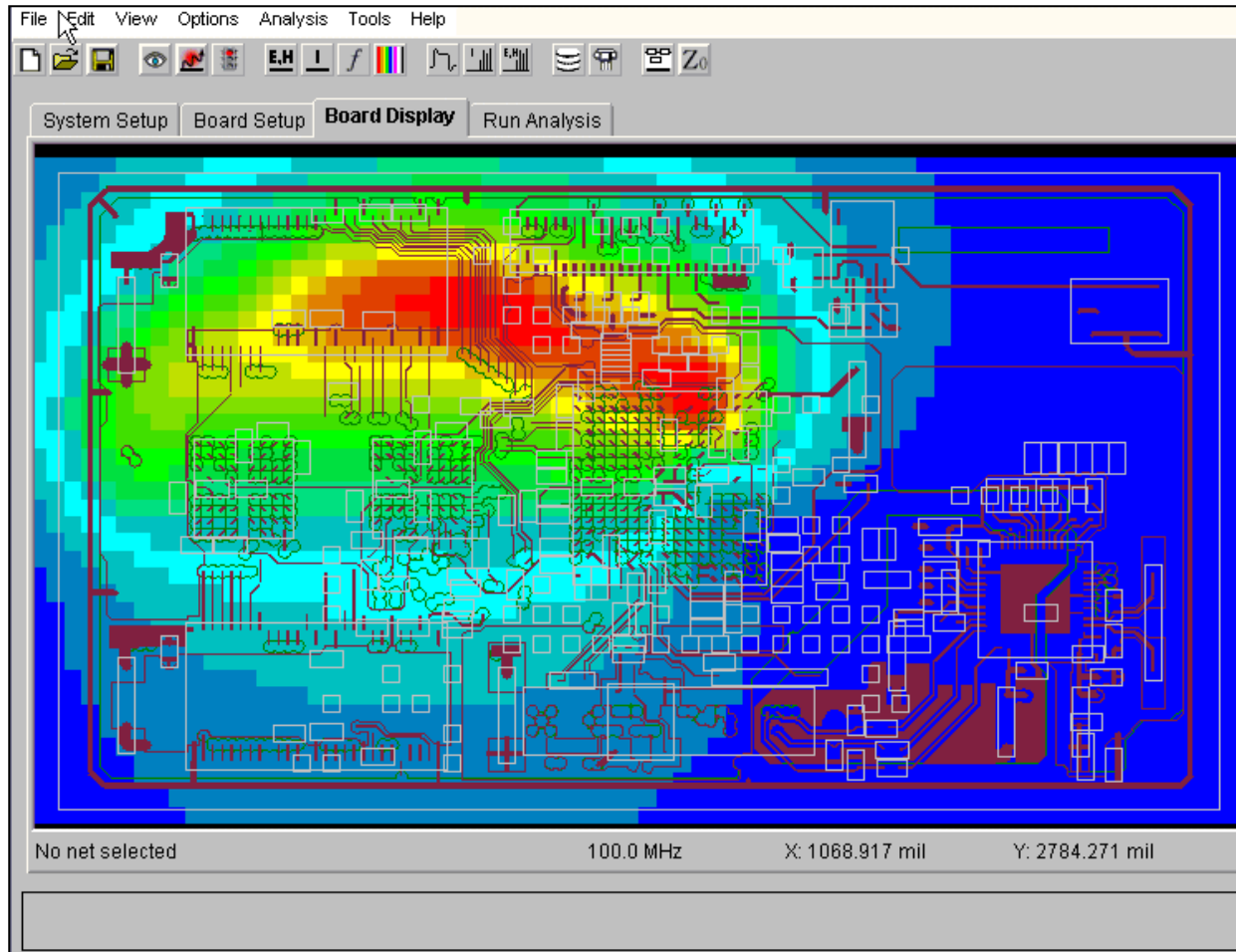
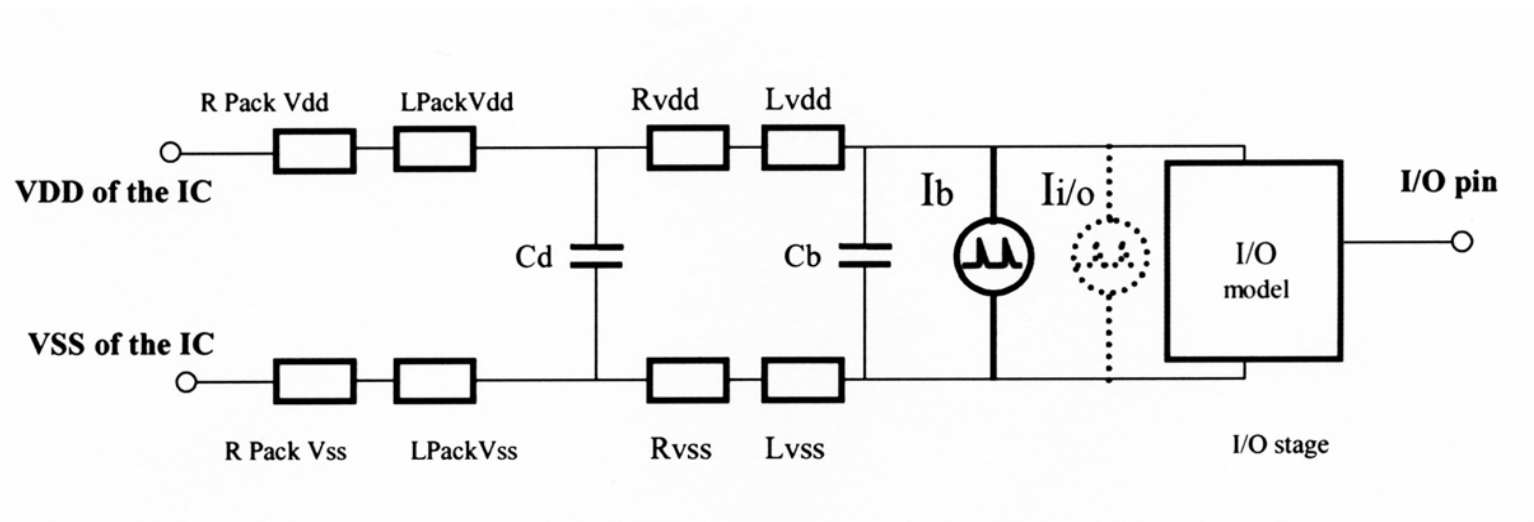


Image Courtesy of Johnson Controls Automotive, Inc. Used with permission



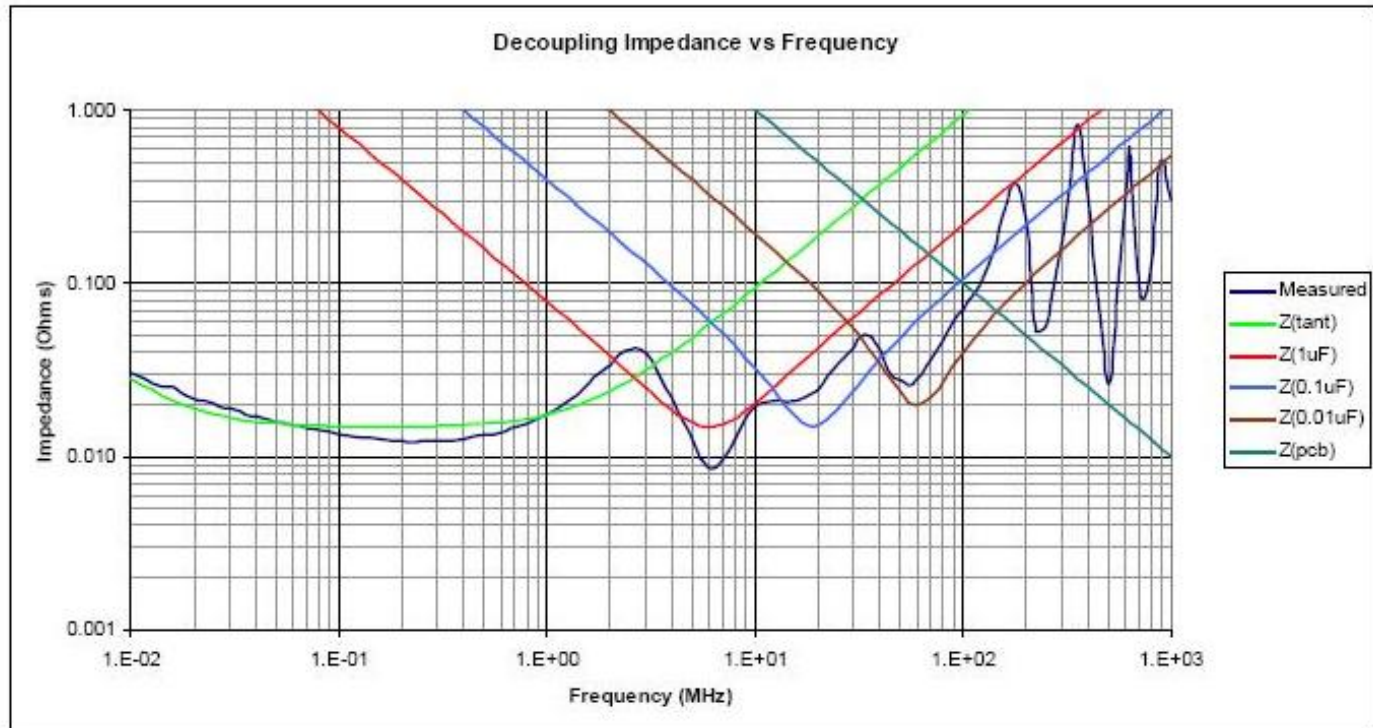
PI and the IEC 62014-3 Proposal



Slide courtesy of Etienne Sicard, INSA-Toulouse

What is happening with IEC 62014-3?

Bypassing the Power Supply for PI



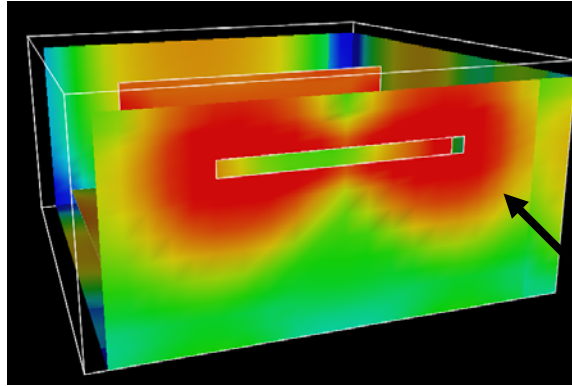
Slide courtesy of Lee Ritchey, Speeding Edge

Reminder to myself: Let's have a discussion of some of the latest PCB techniques for controlling power plane bounce, crosstalk, and emissions

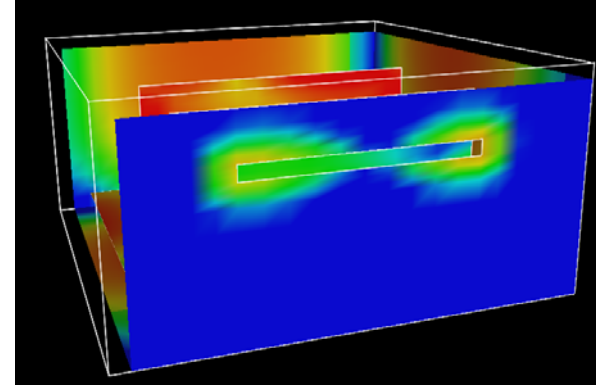


3D Full-Wave EMI Simulators

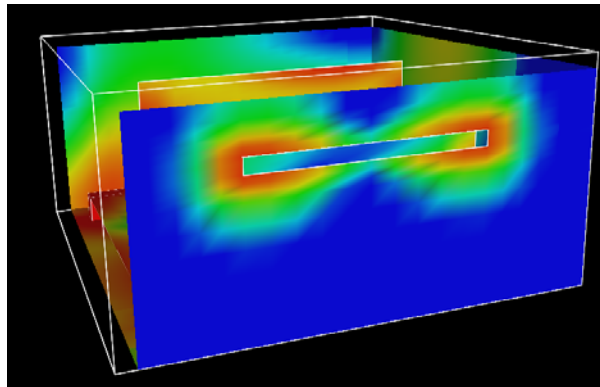
Baseline



Ground Pins Only

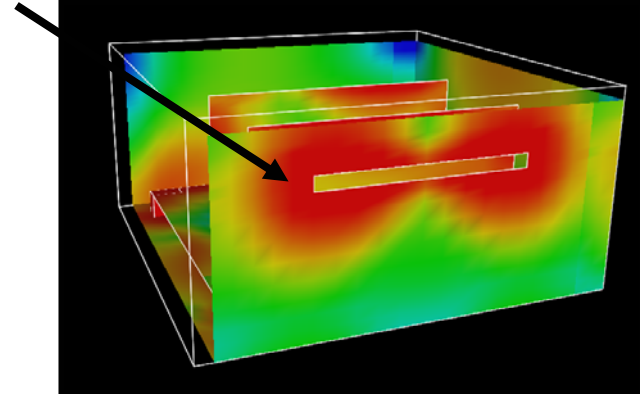


Standoffs Only



Strong Coupling
to Slot-WHY?

Pins and Standoffs

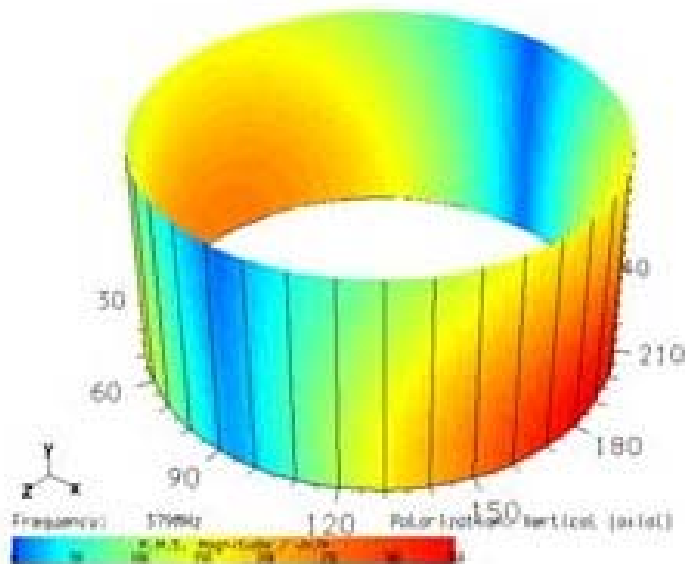


Slide courtesy of FloEMC used with permission



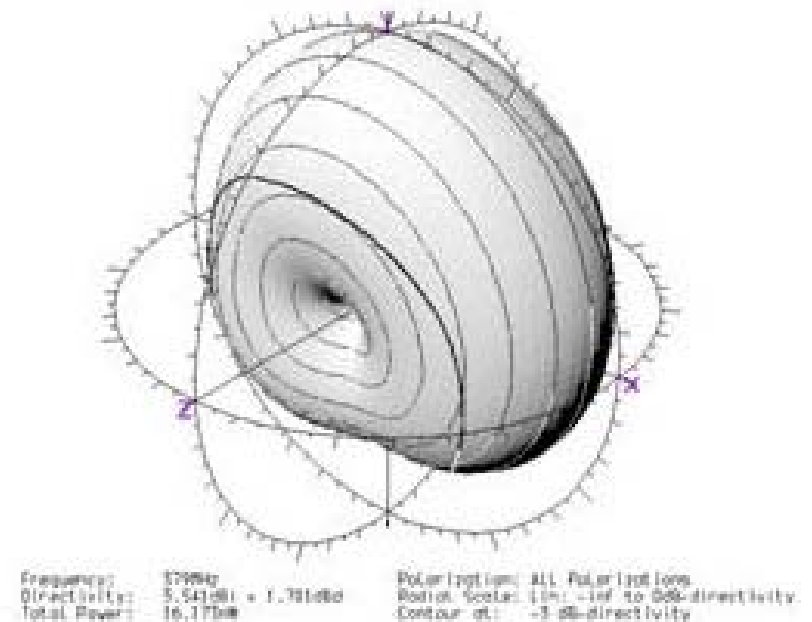
Far-Field EMI Simulators

U1 Star com Box



3m cylinder scan

U1 Star com Box

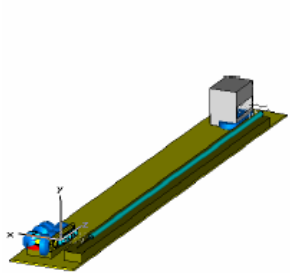


Far-Field radiation

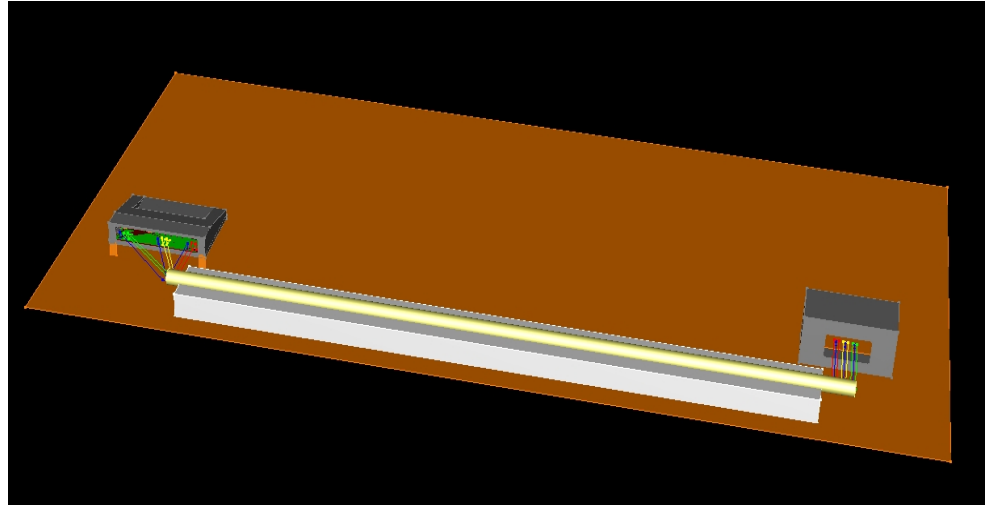
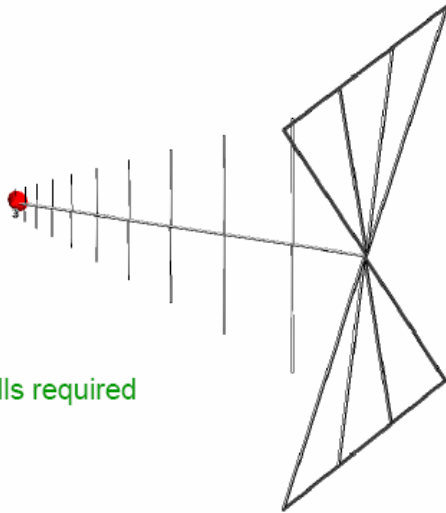
Slide courtesy of FloEMC used with permission



The Virtual Test Bench



85,357,440 meshcells required

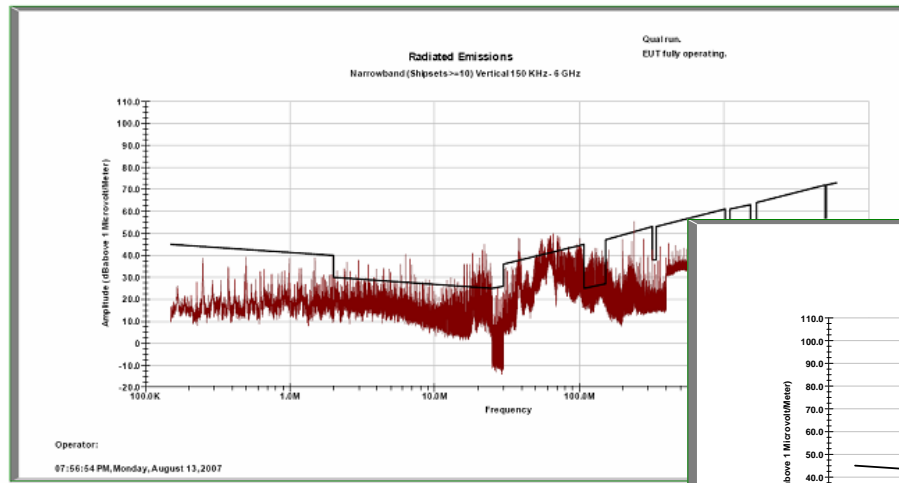


Slide courtesy of Jerry Meyerhoff,
Continental AG, and CST/FloEMC. Used
with permission.



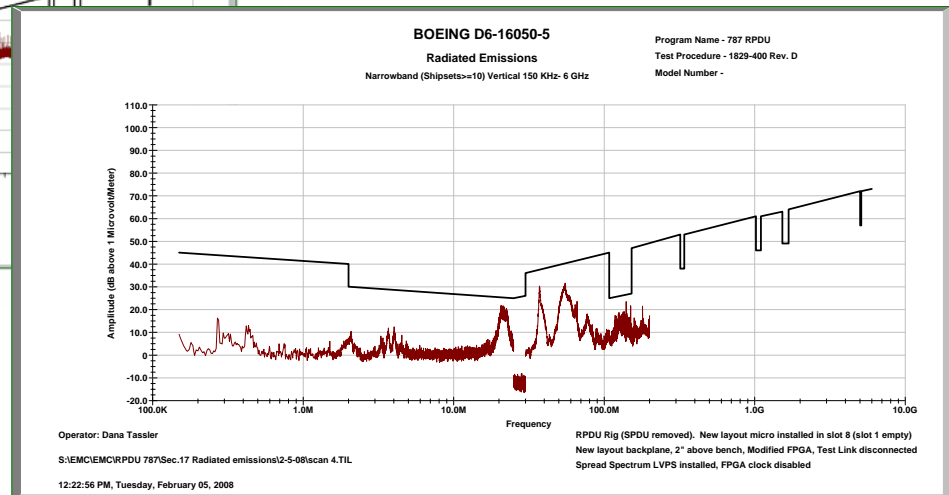
Modelers Need to Use the Language of the Frequency Domain in Talking to EMI Engineers

Plots of a typical regulatory EMI problem and its solution



Vertical NB 150k to 6G

Before



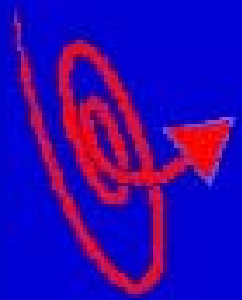
After



Summary

- **EMI**
 - Is driven by the strength and speed of the output driver
 - Is driven by the discontinuities of the transmission net
 - Extends to much higher harmonics than SI issues
- **EMI can be controlled by sophisticated techniques for resolving the problems created by high-speed drivers**
- **EMI issues at the PCB, enclosure, and system level can be studied with sophisticated CEM tools. CEM facilitates the study of EMI design tradeoffs related to models and net design.**
- **Modelers use time domain concepts. EMI Engineers use frequency domain concepts. They need to communicate in each other's language.**





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